

Bayesian Computation for Linear Regression and Analysis of Variance Models

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Statistical **Linear Models**

and

Guide to the Expression of Uncertainty in Measurement (GUM)

- Annex H.3: Linear Regression
- Annex H.5: Analysis of Variance (ANOVA)
- Both annexes
 1. specify: **no Type B uncertainty**
 2. use **frequentist** statistical methods

Frequentist and Bayesian Statistics

Frequentists: define probability of an event as a **relative frequency** of its occurrence. Employ the idea of repeated identical experiments.

Bayesians: define probability of an event as a (possibly subjective) **measure of likelihood** of its occurrence. Does not use repeated identical experiments.

Type A and Type B uncertainty

Type A uncertainties are: “evaluated from the statistical distribution of the results of series of measurements and can be characterized by standard deviations”

Type B uncertainties are: “evaluated from assumed probability distributions based on experience or other information”

EURACHEM/CITAC

Quantifying Uncertainty in Analytical Measurement.

Type A and Type B uncertainties

Type A – mostly obtained by frequentist methods

Type B – require the Bayesian interpretation of probability

ANOVA Example

10V Zener voltage standard is calibrated against a stable voltage reference over 2-week period.

v_{jk} is the k^{th} difference measured on day j

Data from the example:

Day	Daily mean \bar{v}_j in Volts	Daily std s_j in μ Volts
1	10000.172	60
2	10000.116	77
3	10000.013	111
4	10000.144	101
5	10000.106	67
6	10000.031	93
7	10000.060	80
8	10000.125	73
9	10000.163	88
10	10000.041	86

Motivation for the ANOVA model

It is thought to be likely that there will be *random variation* causing the mean (*measurand*) of the observations *to change* from day-to-day.

Frequentist Model and Analysis

(used in the GUM)

- Assumes that the v_{jk} are realizations of V_{jk} from the model:

$$V_{jk} = \mu + \alpha_j + e_{jk}$$
$$j = 1, \dots, 10$$
$$k = 1, \dots, 5$$

- μ is the measurand,
- α_j are random variables representing the day effects, they have 0 mean and variance σ_α
- e_{jk} are random variables representing within-day variability, they have 0 mean and variance σ

Alternative Frequentist Model Formulation

In hierarchical representation:

$$V_{jk} | \theta_j, \sigma^2 \sim N(\theta_j, \sigma^2)$$

Within-day
variability

$$\theta_j | \mu, \sigma_\alpha^2 \sim N(\mu, \sigma_\alpha^2)$$

Between-day
variability

$\theta_j | \mu, \sigma_\alpha^2$ represents conditioning.

Frequentist Analysis

The *value*, that is the estimate of μ is

$$\bar{v}_{..} = \frac{1}{50} \sum_{j=1}^{10} \sum_{k=1}^5 v_{jk}$$

The *standard uncertainty* is an estimate of

$$\sqrt{\frac{1}{10} \left(\frac{\sigma^2}{5} + \sigma_{\alpha}^2 \right)}$$

Results

value = 10000.097V

standard uncertainty = 18 μV , with 9 degrees
of freedom

When **no day effect** is assumed:

value is the same

standard uncertainty = 13 μV , with 49 degrees
of freedom

Add Type B uncertainty

Suppose now that it is necessary to add type B uncertainty in this Example.

That is, that a type B uncertainty for the measurements on day j is given as τ_j .

(For the sake of example, we will assume that 40% of the uncertainty as given in the third column of the table is of type B.)

Bayesian Analysis in general

μ is a random variable with prior distribution $f(\mu)$.

Bayes Theorem

$$f(\mu | v) = \frac{f(v | \mu)f(\mu)}{\int f(v | \mu)f(\mu)d\mu}$$

Used to produce posterior distribution $f(\mu | v)$

Bayesian Analysis - continued

The posterior mean of μ can be used for the *value*.

The posterior standard deviation for the *standard uncertainty*.

Bayesian ANOVA Model with Type B

The experiment in the Example can be represented as:

Likelihood

$$V_{jk} | \theta_j, \sigma_j^2 \sim N(\theta_j, \sigma_j^2)$$

Type A
within-day

$$\theta_j | \delta_j, \tau_j^2 \sim N(\delta_j, \tau_j^2)$$

Type B
within-day

$$\delta_j | \mu, \sigma_\alpha^2 \sim N(\mu, \sigma_\alpha^2)$$

between-days

Non-informative
prior

$$\left\{ \begin{array}{l} \sigma_\alpha \sim U(0, c_\alpha) \\ \mu \sim N(m, \omega^2) \\ \sigma_j^2 \sim \text{Gamma}(a, b) \end{array} \right.$$

Bayesian ANOVA Model

continued

- First level: likelihood as in Frequentist ANOVA
- Second level: type B uncertainty
- Third level: between-days-variability as in Frequentist ANOVA
- Fourth level: prior knowledge about μ , σ_α and σ_i . Usually let c_α , ω , a and b be large to represent no prior knowledge.

Analysis

No closed form solution for:

$$f(\underline{\mu}|\underline{v}) = \frac{\prod_j f(\underline{v}_j | \theta_j, \sigma_j) f(\theta_j | \delta_j, \tau_j) f(\delta_j | \mu, \sigma_\alpha) f(\mu) f(\sigma_\alpha) f(\sigma_j)}{\int \dots \int \prod_j f(\underline{v}_j | \theta_j, \sigma_j) f(\theta_j | \delta_j, \tau_j) f(\delta_j | \mu, \sigma_\alpha) f(\mu) f(\sigma_\alpha) f(\sigma_j) d\mu d\sigma_\alpha d\sigma_j}$$

Use Markov Chain Monte Carlo methods.

Gibbs Sampler

Basic idea:

Given: random variables X and Y

probability distributions $f(X|Y)$ and $f(Y|X)$

Algorithm:

1. For a given starting x_1 , generate y_1 from $f(Y|X)$
2. For y_1 , generate x_2 from $f(X|Y)$
3. Continue....
4. For large enough sample, under certain regularity conditions on $f(X|Y)$ and $f(Y|X)$ we obtain random draws from the joint distribution of X and Y .

Gibbs Sampler

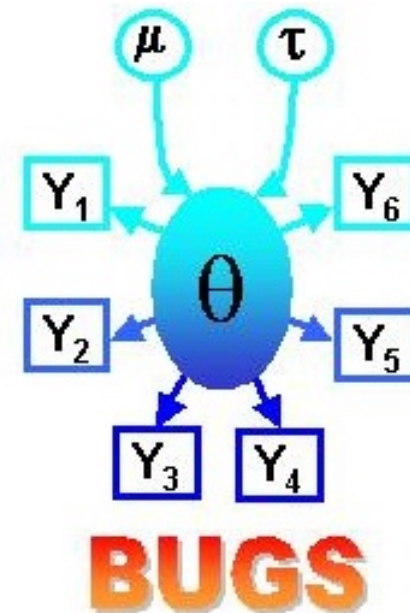
Key References:

S. Geman and D. Geman (1984) IEEE
Trans. On Pattern Recognition and Machine
Intelligence, 6, 721-741

Casella and George (1992) Am. Statistician,
46, 167-174

Programming

Use free software WinBUGS



www.mrc-bsu.cam.ac.uk/bugs/welcome.shtml

Computation for the EXAMPLE

The data is given in terms of the summary statistics: \bar{v}_j and s_j .

The model needs to be *modified* to:

$$\bar{V}_j | \theta_j, \sigma_j^2 \sim N\left(\theta_j, \frac{\sigma_j^2}{k}\right)$$

$$\theta_j | \delta_j, \tau_j^2 \sim N(\delta_j, \tau_j^2)$$

$$\delta_j | \mu, \sigma_\alpha^2 \sim N(\mu, \sigma_\alpha^2)$$

$$(k-1)s_j^2 \sim \text{Gamma}\left(\frac{(k-1)}{2}, \frac{1}{2\sigma_j^2}\right)$$

Computation in WinBUGS

- Need:
1. Program script
 2. Data file
 3. Initial input values

WinBUGS Program for the EXAMPLE

```
{ mu~dnorm(0,1.0E-4)
  sigm~dunif(0,1)
  sigpm<-1/(sigm*sigm)}
```

$f(\mu), f(\sigma_\alpha)$

```
for(i in 1:n){
  typ[i]<-1/(tyb[i])
  theta[i]~dnorm(delta[i],typ[i])
  delta[i]~dnorm(mu,sigpm)
  v[i]~dnorm(theta[i],sg[i])}
```

Modeling of the mean

```
for(i in 1:n){ sig[l]~dunif(0,0.1)
  sg[l]<-1/(sig[l]*sig[l])
  df[i]<-(saml[i]-1)/2.
  ssq[i]<-(saml[i]-1)*s[i]
  sampl[i]<-5
  pg[i]<-sg[i]/2
  ssq[i]~dgamma(df[i],pg[i])}
```

Modeling of the s_i^2

```
For(l in 1:n){ vp[l]~dnorm(theta[l],sg[l])
  dif[l]<-(vp[l]-v[l])
  p[l]<-step(dif[l])}}
```

Predictive p-values

Data File

```
list(s=c(0.00216,0.00336,0.00774,0.00661,0.002,  
0.00552,0.00338,0.00332,0.00447,0.00444),  
tyb=c(0.0014,0.0024,0.0049,0.0041,0.0018,  
0.0035,0.0026,0.0021,0.0031,0.00295),  
v=c(10000.172,10000.116,10000.013,  
10000.144,10000.106,10000.031,10000.06,  
10000.125,10000.163,10000.041),n=10)
```

Initial input values

```
list(mu=0, sigma=.1, sig=c(0.002,  
0.002,0.002,0.002,0.002,0.002,0.002,  
0.002,0.002))
```

Results for the EXAMPLE

Posterior mean of μ

value : 10000.104V

Posterior standard deviation of μ

standard uncertainty : 23 μ V.

(Compare to:

value = 10000.097V

standard uncertainty = 18 μ V, with 9 degrees
of freedom)

Conclusions

- Linear Models can be used with Type B uncertainty
- Requires state-of-knowledge distributions and Bayesian statistics
- Computations can be done using MCMC computation in WinBUGS.